Aura Series – 30 µm Datasheet

The Aura family of Noiseless InGaAs[™] APDs is designed to boost the performance of LIDAR, range finding, optical time domain reflectometry (OTDR), optical coherence tomography (OCT), and other optical systems requiring high-performance infrared sensing from 900 - 1650 nm wavelength.

The Aura series is available with a 30, 80 or 200 μm diameter optical aperture.



Benefits

- Up to 50% greater detection range.
- Up to 12 × higher resolution in imaging.
 - Up to 30% smaller systems.
 - Up to 40% lower system cost.

Features



Note: The term Noiseless InGaAs™ is used to describe Phlux's patented compound semiconductor technology that is used to manufacture APDs with an excess noise factor low enough to enable an APD gain of over 100 without SNR deterioration.



Absolute minimum/maximum ratings

Parameter	Condition	Min	Max	Unit	
Storage temperature		-40	+125	°C	
Operating temperature		-40	+85	°C	
Forward current			1	mA	
Reverse current			100	μΑ	
Reverse voltage			-68	V	
CW optical power	λ =1550 nm		0	dBm	
Damage threshold ⁽¹⁾	λ =1535 nm		30	MW/cm²	

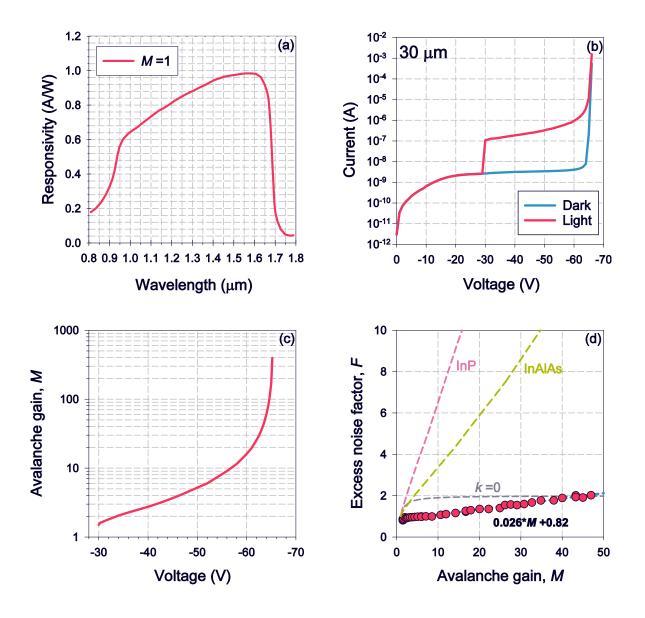
Electrical and optical characteristics at 25 °C

Parameter	Condition	Min	Typical	Max	Unit
Optical window			30		μm
Spectral range			0.95 - 1.7		μm
Responsivity, <i>R</i>	λ =1550 nm, M = 1	0.94	0.98	1.02	A/W
Dark current, I _{dark}	M = 10	1	3	7	nA
Cut-off frequency	M = 10		3.5		GHz
Capacitance	M = 10	0.1	0.15	0.4	pF
Operating voltage, V _{op}	M = 10	-50	-55	-60	V
Breakdown voltage, V _{br}		-60	-65	-70	V
Temperature coefficient of Breakdown voltage, C _{bd}			20		mV/°C
Excess noise factor, F	M = 10		1.08		
	M = 40		1.86		
Spectral noise current, i_{noise} (2)	M = 10		0.05		pA/Hz ^{0.5}
	M = 40		0.24		
Noise equivalent power (3)	M = 10		5.2		- fW/Hz ^{0.5}
	M = 40		5.6		



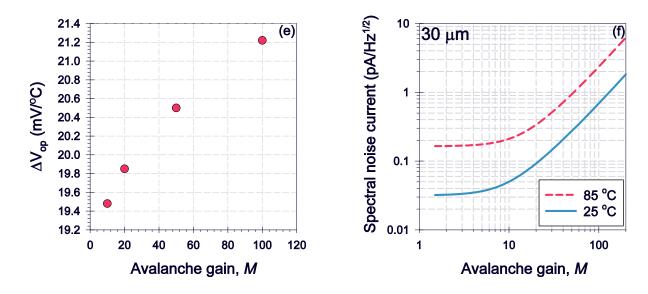
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Typical figures of electrical and optical characteristics at 25 °C





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Typical figures of temperature dependent characteristics

Datasheet

Aura

Aura Series – 30 µm

(1). The experimental set-up for measuring the damage threshold consisted of an APD DC coupled to the TIA. The APD had a current limiting resistors and capacitors on the high voltage bias input. The laser was a 1535 nm diode-pumped solid-state laser source with a 4 ns optical pulse width and 10 Hz repetition rate.

(2). The spectral noise current, i_{noise} , was obtained by the following equation,

$$i_{noise} = \sqrt{2q \left(I_{surf} + I_{bulk} M^2 F \right)}$$

where **q** is the electron charge, **M** is the avalanche gain, **F** is the excess noise factor. The surface component, I_{surf} , and bulk component, I_{bulk} , of dark current, I_{dark} , were extracted by the equation, $I_{dark} = I_{surf} + M^*I_{bulk}$.

(3). The theoretical noise equivalent power (NEP) values can be calculated using the equation below,

$$\begin{split} NEP &= \frac{1}{R_m} (\sqrt{i_{noise}^2 + \sigma_{amp}^2}) \\ &= \frac{1}{R_m} (\sqrt{2q \left(I_{surf} + I_{bulk} M^2 F \right) + \sigma_{amp}^2}) \end{split}$$

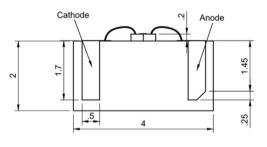
where \mathbf{R}_m is the multiplied responsivity value ($\mathbf{R} * \mathbf{M}$), $\mathbf{\sigma}_{amp}$ is the external amplifier input noise. The NEP values at M = 10 & 40 were calculated by excluding the external amplifier input noise $\mathbf{\sigma}_{amp}$.

Additional technical information available upon request.



Package Mechanical Dimensions

CHIP ON SUBMOUNT



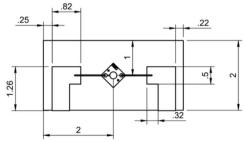


Diagram units in mm

Die attach = Low outgas epoxy Ceramic = 96% Alumina Solder pad metal = Gold Metal thickness = 10 µm (±2 µm)

TO-46 3 PIN (HIGH PROFILE)

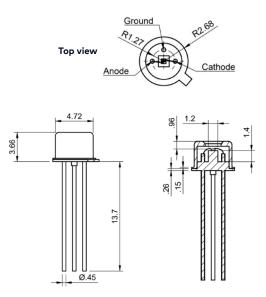


Diagram units in mm

Pin metal = Gold

Optical window AR coated with >98% transmission at 1550nm



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Package Mechanical Dimensions

SMD

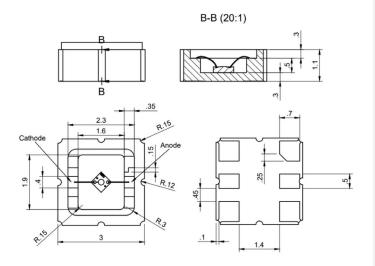


Diagram units in mm

Optical window AR coated with >98% transmission at 1550nm

Please note, product specifications are subject to change without prior notice.



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